AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions and listings of claims in the application.

LISTING OF CLAIMS

1. (Currently Amended) A method for measuring thickness of an optical disc by using an interference effect of the an optical disc layer, comprising the steps of:

detecting an intensity of a reflective light according to a wavelength of a light as spectrum data for each wavelength;

converting the detected spectrum data for each wavelength into a spectrum value as a function of a wavelength that and a refractive index is reflected; and

detecting a position where the intensity of the reflective light has a peak as a thickness of a spacer layer and a cover layer respectively by converting the converted value into a length of an interference area for representing a layer thickness of the optical disc by the Fast Fourier Transform.

2. (Currently Amended) The method of claim 1, wherein in said converting step, the spectrum value as a function of a wavelength that has a refractive index is reflected is of $n(\lambda)/2\lambda$.

- 3. (Previously Presented) The method of claim 1, wherein the optical disc layer comprises the spacer layer with a refractive index n_1 and the cover layer with a refractive index n_2 different from the refractive index n_1 .
- 4. (Previously Presented) The method of claim 3, wherein respective positions d_1 and d_2 where the intensity of the light obtained by reflecting the refractive index into a function of a wavelength become a peak value are obtained as the thickness.
- 5. (Currently Amended) The method of claim 1, wherein in <u>said</u> converting step, an equation for processing the spectrum that the refractive index is reflected into the function of wavelength is expressed as following:

$$2n(\lambda)d = m\lambda$$

$$2n(\lambda + \Delta\lambda)d = (m-1)(\lambda + \Delta\lambda)$$

wherein, d is a thickness, n is a refractive index of the optical disc layer, λ is wavelength, and m is integer value.

6. (Cancelled)